

**Search Notes**

Application/Control No.

10/713,117

Examiner

Michael Trinh

Applicant(s)/Patent under  
Reexamination

LEE ET AL.

Art Unit

2822

**SEARCHED**

Class	Subclass	Date	Examiner
438	276	4/11/2005	MT
438	277	4/11/2005	MT
438	278	4/11/2005	MT
438	275	4/11/2005	MT
438	257	4/11/2005	MT
438	258	4/11/2005	MT
438	201	4/11/2005	MT
438	200	4/11/2005	MT

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Databases: USPAT, PGPUB, JPO, EPO, IBM-TDB, USOCR	4/11/2005	MT

**INTERFERENCE SEARCHED**

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